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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	I²C, IrDA, LINbus, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, I²S, POR, PWM, WDT
Number of I/O	80
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.68V ~ 3.6V
Data Converters	A/D 15x12b; D/A 1x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-TQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/atsam4ls2ca-au

Table 3-1. 100-pin GPIO Controller Function Multiplexing (Sheet 2 of 4)

ATSAM4LC		ATSAM4LS		Pin	GPIO	Supply	GPIO Functions						
QFN	VFBGA	QFN	VFBGA				A	B	C	D	E	F	G
66	J7	66	J7	PA16	16	LCDA	USART1 TXD	TC0 CLK2	EIC EXTINT1	PARC PCDATA7		LCDCA SEG8	CATB SENSE11
67	H6	67	H6	PA17	17	LCDA	USART2 RTS	ABDACB DAC0	EIC EXTINT2	PARC PCCK		LCDCA SEG9	CATB SENSE12
76	K10	76	K10	PA18	18	LCDA	USART2 CLK	ABDACB DACN0	EIC EXTINT3	PARC PCEN1		LCDCA SEG18	CATB SENSE13
77	J10	77	J10	PA19	19	LCDA	USART2 RXD	ABDACB DAC1	EIC EXTINT4	PARC PCEN2	SCIF GCLK0	LCDCA SEG19	CATB SENSE14
78	H10	78	H10	PA20	20	LCDA	USART2 TXD	ABDACB DACN1	EIC EXTINT5	GLOC IN0	SCIF GCLK1	LCDCA SEG20	CATB SENSE15
91	E9	91	E9	PA21	21	LCDC	SPI MISO	USART1 CTS	EIC EXTINT6	GLOC IN1	TWIM2 TWD	LCDCA SEG34	CATB SENSE16
92	E10	92	E10	PA22	22	LCDC	SPI MOSI	USART2 CTS	EIC EXTINT7	GLOC IN2	TWIM2 TWCK	LCDCA SEG35	CATB SENSE17
95	D6	95	D6	PA23	23	LCDC	SPI SCK	TWIMS0 TWD	EIC EXTINT8	GLOC IN3	SCIF GCLK IN0	LCDCA SEG38	CATB DIS
96	D10	96	D10	PA24	24	LCDC	SPI NPCS0	TWIMS0 TWCK		GLOC OUT0	SCIF GCLK IN1	LCDCA SEG39	CATB SENSE18
98	D9	98	D9	PA25	25	VDDIO	USBC DM	USART2 RXD					CATB SENSE19
99	C9	99	C9	PA26	26	VDDIO	USBC DP	USART2 TXD					CATB SENSE20
		51	K1	PA27	27	LCDA	SPI MISO	IISC ISCK	ABDACB DAC0	GLOC IN4	USART3 RTS		CATB SENSE0
		52	J1	PA28	28	LCDA	SPI MOSI	IISC ISDI	ABDACB DACN0	GLOC IN5	USART3 CTS		CATB SENSE1
		53	K2	PA29	29	LCDA	SPI SCK	IISC IWS	ABDACB DAC1	GLOC IN6	USART3 CLK		CATB SENSE2
		56	K4	PA30	30	LCDA	SPI NPCS0	IISC ISDO	ABDACB DACN1	GLOC IN7	USART3 RXD		CATB SENSE3
		57	K5	PA31	31	LCDA	SPI NPCS1	IISC IMCK	ABDACB CLK	GLOC OUT1	USART3 TXD		CATB DIS
20	J3	20	J3	PB00	32	VDDIN	TWIMS1 TWD	USART0 RXD					CATB SENSE21
21	D5	21	D5	PB01	33	VDDIN	TWIMS1 TWCK	USART0 TXD	EIC EXTINT0				CATB SENSE22
22	E5	22	E5	PB02	34	VDDANA	ADCIFE AD3	USART1 RTS	ABDACB DAC0	IISC ISCK	ACIFC ACBN0		CATB SENSE23
23	C4	23	C4	PB03	35	VDDANA	ADCIFE AD4	USART1 CLK	ABDACB DACN0	IISC ISDI	ACIFC ACBP0		CATB DIS
28	C1	28	C1	PB04	36	VDDANA	ADCIFE AD5	USART1 RXD	ABDACB DAC1	IISC ISDO	DACC EXT TRIG0		CATB SENSE24
29	B1	29	B1	PB05	37	VDDANA	ADCIFE AD6	USART1 TXD	ABDACB DACN1	IISC IMCK			CATB SENSE25
45	G3	45	G3	PB06	38	LCDA	USART3 RTS		GLOC IN4	IISC IWS		LCDCA SEG22	CATB SENSE26
46	H1	46	H1	PB07	39	LCDA	USART3 CTS		GLOC IN5	TC0 A0		LCDCA SEG21	CATB SENSE27

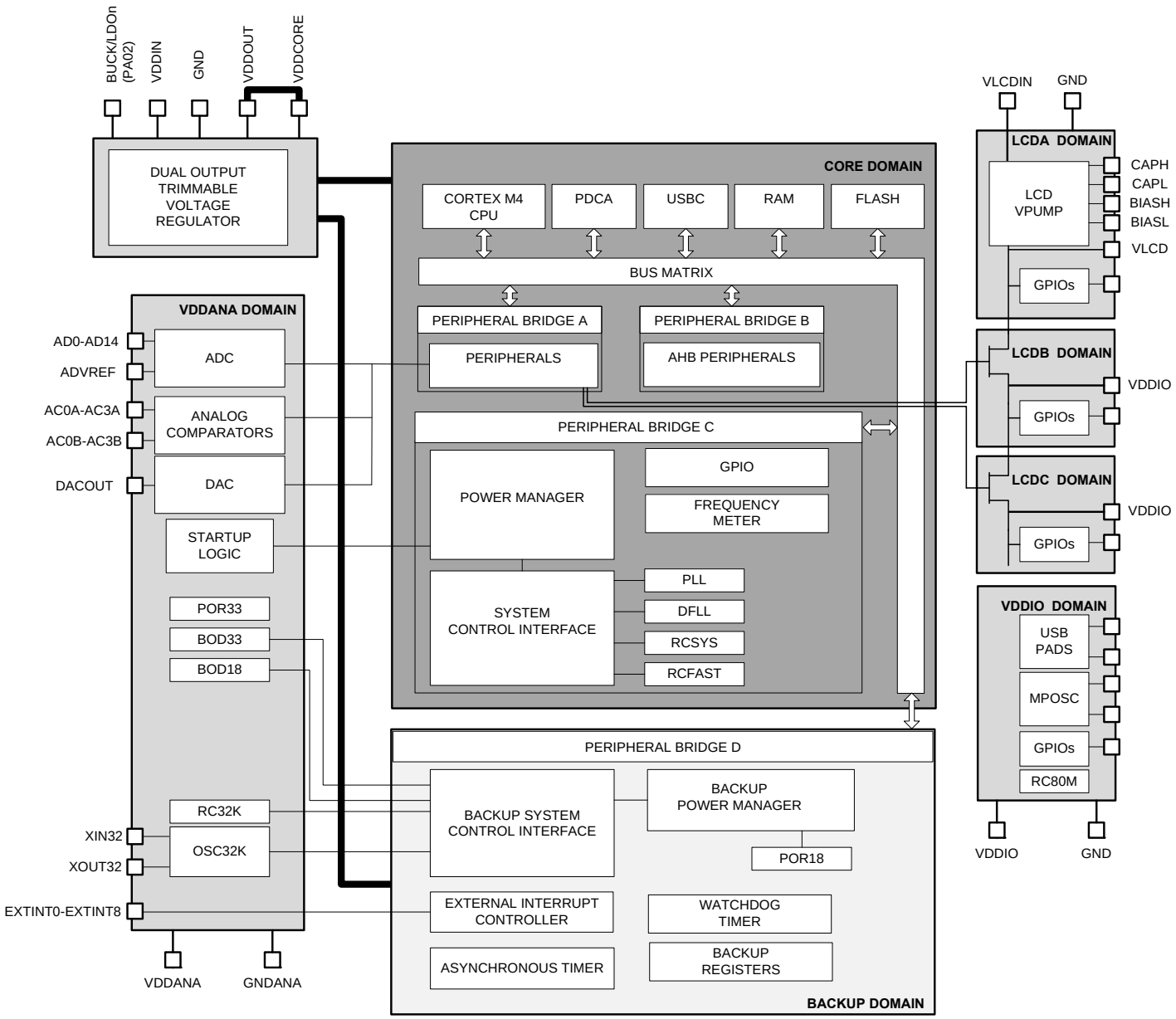
3.3 Signals Description

The following table gives details on signal names classified by peripheral.

Table 3-8. Signal Descriptions List (Sheet 1 of 4)

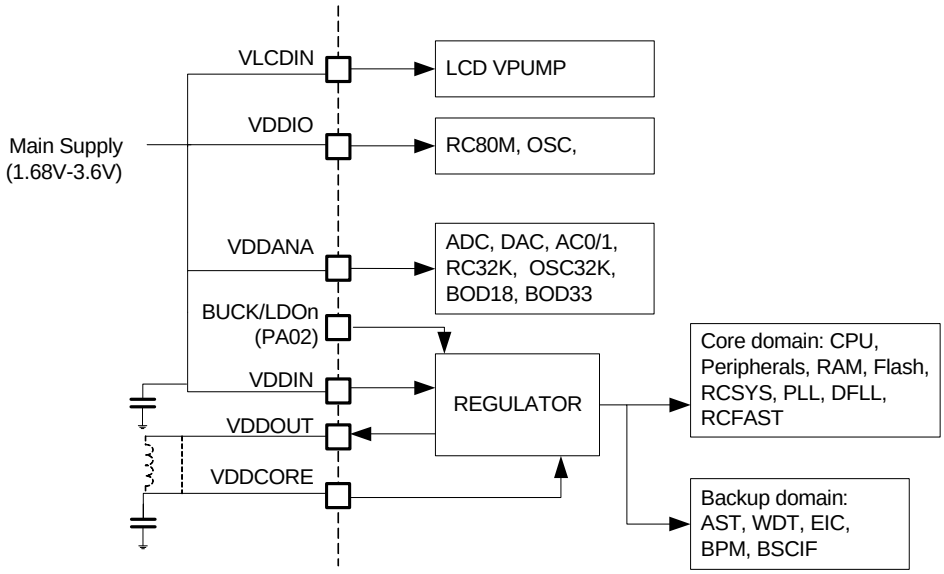
Signal Name	Function	Type	Active Level	Comments
Audio Bitstream DAC - ABDACB				
CLK	D/A clock output	Output		
DAC1 - DAC0	D/A bitstream outputs	Output		
DACN1 - DACN0	D/A inverted bitstream outputs	Output		
Analog Comparator Interface - ACIFC				
ACAN1 - ACAN0	Analog Comparator A negative references	Analog		
ACAP1 - ACAP0	Analog Comparator A positive references	Analog		
ACBN1 - ACBN0	Analog Comparator B negative references	Analog		
ACBP1 - ACBP0	Analog Comparator B positive references	Analog		
ADC controller interface - ADCIFE				
AD14 - AD0	Analog inputs	Analog		
ADVREFP	Positive voltage reference	Analog		
TRIGGER	External trigger	Input		
Backup System Control Interface - BSCIF				
XIN32	32 kHz Crystal Oscillator Input	Analog/ Digital		
XOUT32	32 kHz Crystal Oscillator Output	Analog		
Capacitive Touch Module B - CATB				
DIS	Capacitive discharge line	Output		
SENSE31 - SENSE0	Capacitive sense lines	I/O		
DAC Controller - DACC				
DAC external trigger	DAC external trigger	Input		
DAC voltage output	DAC voltage output	Analog		
Enhanced Debug Port For ARM Products - EDP				
TCK/SWCLK	JTAG / SW Debug Clock	Input		
TDI	JTAG Debug Data In	Input		
TDO/TRACESWO	JTAG Debug Data Out / SW Trace Out	Output		
TMS/SWDIO	JTAG Debug Mode Select / SW Data	I/O		
External Interrupt Controller - EIC				
EXTINT8 - EXTINT0	External interrupts	Input		
Glue Logic Controller - GLOC				
IN7 - IN0	Lookup Tables Inputs	Input		
OUT1 - OUT0	Lookup Tables Outputs	Output		

Figure 6-2. ATSAM4LC Power Domain Diagram



The internal regulator is connected to the VDDIN pin and its output VDDOUT feeds VDDCORE in linear mode or through an inductor in switching mode. Figure 6-4 shows the power schematics to be used. All I/O lines will be powered by the same power (V_{VDDIN}=V_{VDDIO}=V_{VDDANA}).

Figure 6-4. Single Supply Mode



6.2.3 LCD Power Modes

6.2.3.1 Principle

LCD lines is powered using the device internal voltage sources provided by the LCDPWR block. When enabled, the LCDPWR blocks will generate the VLCD, BIASL, BIASH voltages.

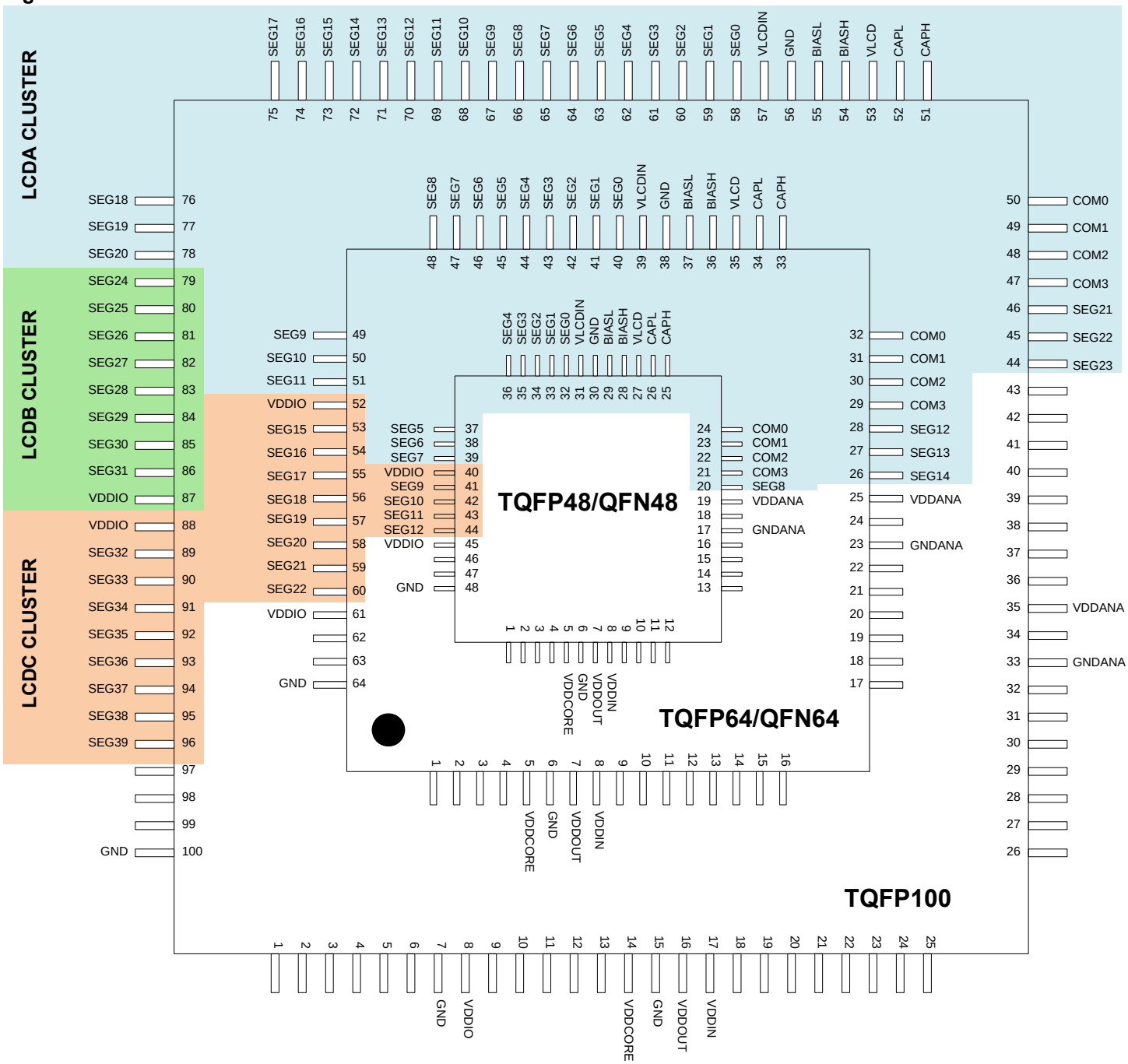
LCD pads are splitted into three clusters that can be powered independently namely clusters A, B and C. A cluster can either be in GPIO mode or in LCD mode.

When a cluster is in GPIO mode, its VDDIO pin must be powered externally. None of its GPIO pin can be used as a LCD line

When a cluster is in LCD mode, each clusters VDDIO pin can be either forced externally (1.8-3.6V) or unconnected (nc). GPIOs in a cluster are not available when it is in LCD mode. A cluster is set in LCD mode by the LCDCA controller when it is enabled depending on the number of segments configured. The LCDPWR block is powered by the VLCDIN pin inside cluster A

When LCD feature is not used, VLCDIN must be always powered (1.8-3.6V). VLCD, CAPH, CAPL, BIASH, BIASL can be left unconnected in this case

Figure 6-5. LCD clusters in the device



6.2.3.2 *Internal LCD Voltage*

In this mode the LCD voltages are internally generated. Depending of the number of segments required by the application, LCDB and LDCC clusters VDDIO pin must be unconnected (nc) or

6.2.4 Power-up Sequence

6.2.4.1 Maximum Rise Rate

To avoid risk of latch-up, the rise rate of the power supplies must not exceed the values described in Table 9-3 on page 100.

6.2.4.2 Minimum Rise Rate

The integrated Power-on Reset (POR33) circuitry monitoring the VDDIN powering supply requires a minimum rise rate for the VDDIN power supply.

See Table 9-3 on page 100 for the minimum rise rate value.

If the application can not ensure that the minimum rise rate condition for the VDDIN power supply is met, the following configuration can be used:

- A logic “0” value is applied during power-up on pin RESET_N until VDDIN rises above 1.6 V.

6.3 Startup Considerations

This section summarizes the boot sequence of the ATSAM4L8/L4/L2. The behavior after power-up is controlled by the Power Manager. For specific details, refer to Section 9. ”Power Manager (PM)” on page 677.

6.3.1 Starting of Clocks

After power-up, the device will be held in a reset state by the power-up circuitry for a short time to allow the power to stabilize throughout the device. After reset, the device will use the System RC Oscillator (RCSYS) as clock source. Refer to Section 9. ”Electrical Characteristics” on page 99 for the frequency for this oscillator.

On system start-up, the DFLL and the PLLs are disabled. Only the necessary clocks are active allowing software execution. Refer to Section 3-6 ”Maskable Module Clocks in AT32UC3B.” on page 24 to know the list of peripheral clock running.. No clocks have a divided frequency; all parts of the system receive a clock with the same frequency as the System RC Oscillator.

6.3.2 Fetching of Initial Instructions

After reset has been released, the Cortex M4 CPU starts fetching PC and SP values from the reset address, which is 0x00000000. Refer to the ARM Architecture Reference Manual for more information on CPU startup. This address points to the first address in the internal Flash.

The code read from the internal flash is free to configure the clock system and clock sources.

6.4 Power-on-Reset, Brownout and Supply Monitor

The SAM4L embeds four features to monitor, warm, and/or reset the device:

- POR33: Power-on-Reset on VDDANA
- BOD33: Brownout detector on VDDANA
- POR18: Power-on-Reset on VDDCORE
- BOD18: Brownout detector on VDDCORE

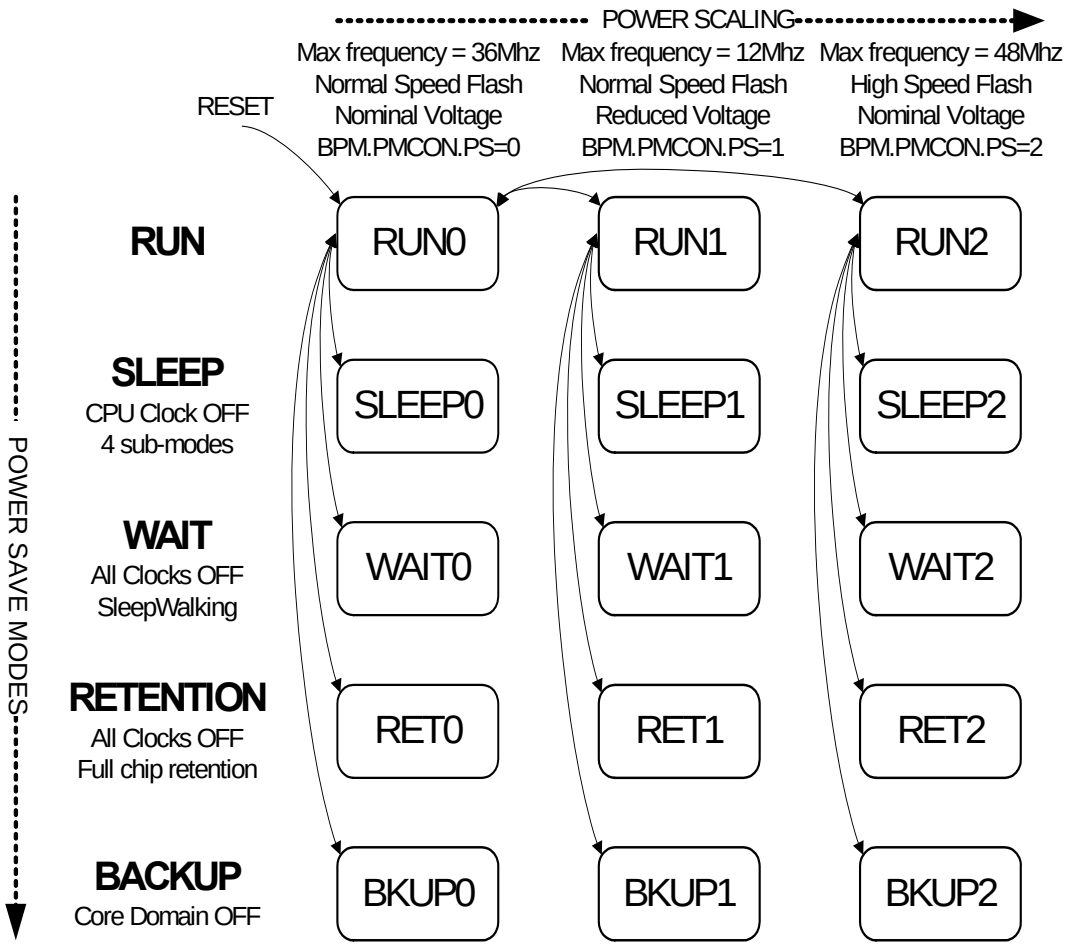
7. Low Power Techniques

The ATSAM4L8/L4/L2 supports multiple power configurations to allow the user to optimize its power consumption in different use cases. The Backup Power Manager (BPM) implements different solutions to reduce the power consumption:

- The Power Save modes intended to reduce the logic activity and to adapt the power configuration. See "Power Save Modes" on page 55.
- The Power Scaling intended to scale the power configuration (voltage scaling of the regulator). See "Power Scaling" on page 60.

These two techniques can be combined together.

Figure 7-1. Power Scaling and Power Save Mode Overview



7.1 Power Save Modes

Refer to Section 6. "Power and Startup Considerations" on page 46 to get definition of the core and the backup domains.

At power-up or after a reset, the ATSAM4L8/L4/L2 is in the RUN0 mode. Only the necessary clocks are enabled allowing software execution. The Power Manager (PM) can be used to adjust the clock frequencies and to enable and disable the peripheral clocks.

When the CPU is entering a Power Save Mode, the CPU stops executing code. The user can choose between four Power Save Modes to optimize power consumption:

- SLEEP mode: the Cortex-M4 core is stopped, optionally some clocks are stopped, peripherals are kept running if enabled by the user.
- WAIT mode: all clock sources are stopped, the core and all the peripherals are stopped except the modules running with the 32kHz clock if enabled. This is the lowest power configuration where SleepWalking is supported.
- RETENTION mode: similar to the WAIT mode in terms of clock activity. This is the lowest power configuration where the logic is retained.
- BACKUP mode: the Core domain is powered off, the Backup domain is kept powered.

A wake up source exits the system to the RUN mode from which the Power Save Mode was entered.

A reset source always exits the system from the Power Save Mode to the RUN0 mode.

The configuration of the I/O lines are maintained in all Power Save Modes. Refer to Section 9. ”Backup Power Manager (BPM)” on page 677.

7.1.1 SLEEP mode

The SLEEP mode allows power optimization with the fastest wake up time.

The CPU is stopped. To further reduce power consumption, the user can switch off modules-clocks and synchronous clock sources through the BPM.PMCON.SLEEP field (See Table 7-1). The required modules will be halted regardless of the bit settings of the mask registers in the Power Manager (PM.AHBMASK, PM.APBxMASK).

Table 7-1. SLEEP mode Configuration

BPM.PSAVE.SLEEP	CPU clock	AHB clocks	APB clocks GCLK	Clock sources: OSC, RCFAST, RC80M, PLL, DFLL	RCSYS	OSC32K RC32K(2)	Wake up Sources
0	Stop	Run	Run	Run	Run	Run	Any interrupt
1	Stop	Stop	Run	Run	Run	Run	Any interrupt(1)
2	Stop	Stop	Stop	Run	Run	Run	Any interrupt(1)
3	Stop	Stop	Stop	Stop	Run	Run	Any interrupt(1)

Notes: 1. from modules with clock running.
2. OSC32K and RC32K will only remain operational if pre-enabled.

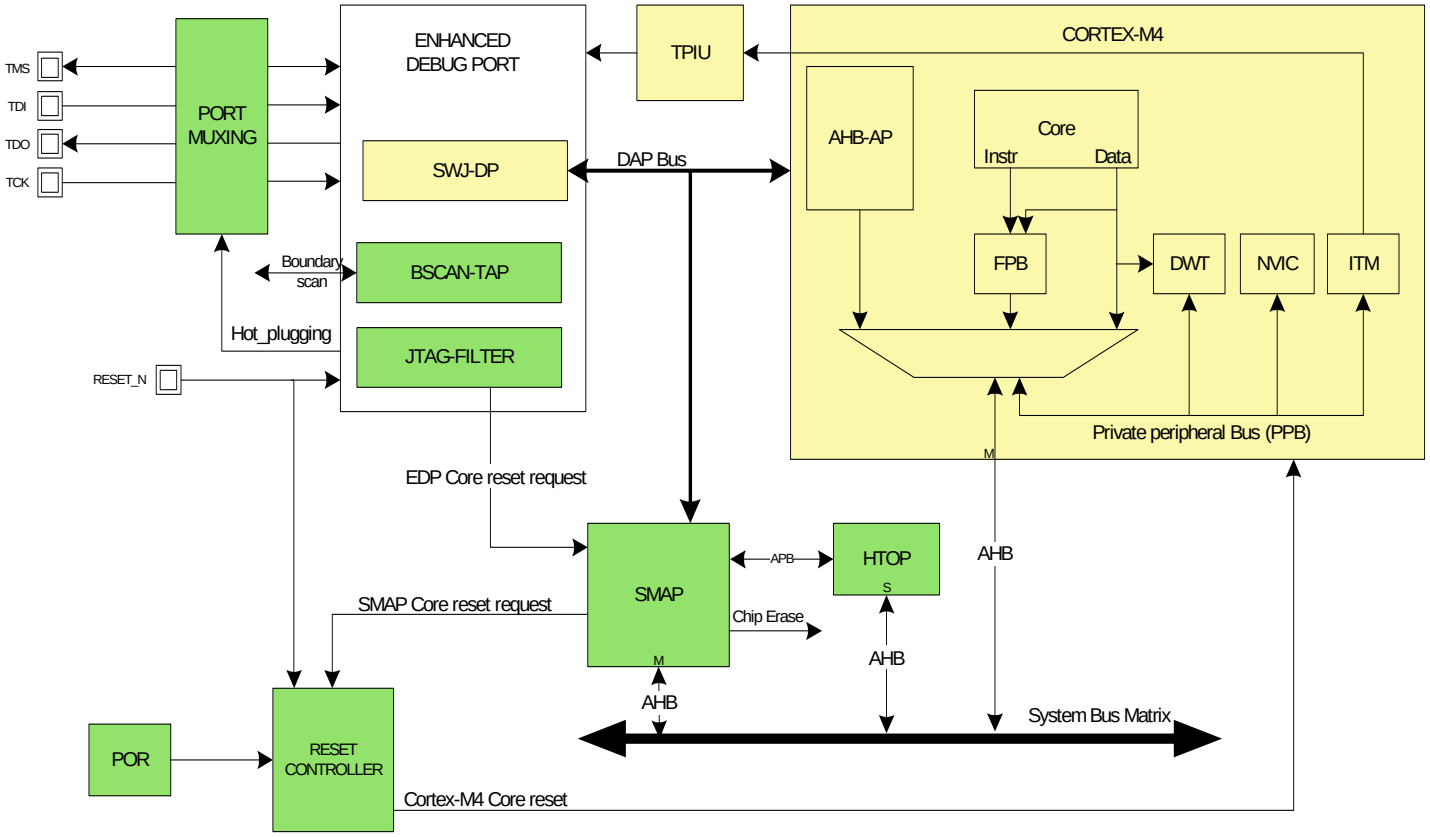
7.1.1.1 Entering SLEEP mode

The SLEEP mode is entered by executing the WFI instruction.

Additionally, if the SLEEPONEXIT bit in the Cortex-M4 System Control Register (SCR) is set, the SLEEP mode will also be entered when the Cortex-M4 exits the lowest priority ISR. This

8.3 Block diagram

Figure 8-1. Debug and Test Block Diagram



note: Boxes with a plain corner are SAM4L specific.

8.4 I/O Lines Description

Refer to Section 1.1.4 ”I/O Lines Description” on page 4.

Table 8-4. Instruction Description (Continued)

Instruction	Description
DR Size	Shows the number of bits in the data register chain when this instruction is active. Example: 32 bits
DR input value	Shows which bit pattern to shift into the data register in the Shift-DR state when this instruction is active.
DR output value	Shows the bit pattern shifted out of the data register in the Shift-DR state when this instruction is active.

8.7.14 JTAG Instructions

Refer to the ARM Debug Interface v5.1 Architecture Specification for more details on ABORT, DPACC, APACC and IDCODE instructions.

8.7.14.1 EXTEST

This instruction selects the boundary-scan chain as Data Register for testing circuitry external to the chip package. The contents of the latched outputs of the boundary-scan chain is driven out as soon as the JTAG IR-register is loaded with the EXTEST instruction.

Starting in Run-Test/Idle, the EXTEST instruction is accessed the following way:

1. Select the IR Scan path.
2. In Capture-IR: The IR output value is latched into the shift register.
3. In Shift-IR: The instruction register is shifted by the TCK input.
4. In Update-IR: The data from the boundary-scan chain is applied to the output pins.
5. Return to Run-Test/Idle.
6. Select the DR Scan path.
7. In Capture-DR: The data on the external pins is sampled into the boundary-scan chain.
8. In Shift-DR: The boundary-scan chain is shifted by the TCK input.
9. In Update-DR: The data from the scan chain is applied to the output pins.
10. Return to Run-Test/Idle.

Table 8-5. EXTEST Details

Instructions	Details
IR input value	**0000** (0x0)
IR output value	p00s
DR Size	Depending on boundary-scan chain, see BSDL-file.
DR input value	Depending on boundary-scan chain, see BSDL-file.
DR output value	Depending on boundary-scan chain, see BSDL-file.

8.7.14.2 SAMPLE_PRELOAD

This instruction takes a snap-shot of the input/output pins without affecting the system operation, and pre-loading the scan chain without updating the DR-latch. The boundary-scan chain is selected as Data Register.

Starting in Run-Test/Idle, the Device Identification register is accessed in the following way:

8.9.9 Unlimited Flash User Page Read Access

The SMAP can access the User page even if the protected state is set. Prior to operate such an access, the user should check that the module is not busy by checking that SR.STATE is equal to zerp. Once the offset of the word to access inside the page is written in ADDR.ADDR, the read operation can be initiated by writing a one in CR.FSPR. The SR.STATE field will indicate the FSPR state. Addresses written to ADDR.ADDR must be world aligned. Failing to do so will result in unpredictable behavior. The result can be read in the DATA register as soon as SR.DONE rises. The ADDR field is used as an offset in the page, bits outside a page boundary will be silently discarded. The ADDR register is automatically incremented at the end of the read operation making possible to dump consecutive words without writing the next offset into ADDR.ADDR.

8.9.10 32-bit Cyclic Redundancy Check (CRC)

The SMAP unit provides support for calculating a Cyclic Redundancy Check (CRC) value for a memory area. The algorithm used is the industry standard CRC32 algorithm using the generator polynomial 0xEDB88320.

8.9.10.1 Starting CRC Calculation

To calculate CRC for a memory range, the start address must be written into the ADDR register, and the size of the memory range into the LENGTH register. Both the start address and the length must be word aligned.

The initial value used for the CRC calculation must be written to the DATA register. This value will usually be 0xFFFFFFFF, but can be e.g. the result of a previous CRC calculation if generating a common CRC of separate memory blocks.

Once completed, the calculated CRC value can be read out of the DATA register. The read value must be inverted to match standard CRC32 implementations, or kept non-inverted if used as starting point for subsequent CRC calculations.

If the device is in protected state, it is only possible to calculate the CRC of the whole flash array. In most cases this area will be the entire onboard nonvolatile memory. The ADDR, LENGTH, and DATA registers will be forced to predefined values once the CRC operation is started, and user-written values are ignored. This allows the user to verify the contents of a protected device.

The actual test is started by writing a one in CR.CRC. A running CRC operation can be cancelled by disabling the module (write a one in CR.DIS). This has the effect of resetting the module. The module has to be restarted by issuing an enable command (write a one in CR.EN).

8.9.10.2 Interpreting the Results

The user should monitor the SR register (Refer to Section 8.9.11.2 ”Status Register” on page 83). When the operation is completed SR.DONE is set. Then the SR.BERR and SR.FAIL must be read to ensure that no bus error nor functional error occured.

8.9.11 SMAP User Interface

Table 8-9. SMAP Register Memory Map

Offset	Register	Register Name	Access (unprotected)	Access (protected)	Reset
0x0000	Control Register	CR	Write-Only	Write-Only (partial)(2)	0x00000000
0x0004	Status Register	SR	Read-Only	Read-Only	0x00000000
0x0008	Status Clear Register	SCR	Write-Only	Write-Only (partial)(3)	0x00000000
0x000C	Address Register	ADDR	Read/Write	Read/Write (partial)(4)	0x00000000
0x0010	Length Register	LENGTH	Read/Write	denied	0x00000000
0x0014	Data Register	DATA	Read/Write	Read/Write (partial)(4)	0x00000000
0x0028	VERSION Register	VERSION	Read-Only	Read-Only	-(1)
0x00F0	Chip ID Register	CIDR	Read-Only	Read-Only	-(1)
0x00F4	Chip ID Extension Register	EXID	Read-Only	Read-Only	-(1)
0x00FC	AP Identification register	IDR	Read-Only	Read-Only	0x003E0000

Note:
1. The reset value for this register is device specific. Refer to the Module Configuration section at the end of this chapter.
2. CR.MBIST is ignored
3. SCR.HCR is ignored
4. Access is not allowed when an operation is ongoing

8.9.11.1 Control Register

Name: CR

Access Type: Write-Only

Offset: 0x00

Reset Value: 0x00000000

31	30	29	28	27	26	25	24
-	-	-	-	-	-	-	-

23	22	21	20	19	18	17	16
-	-	-	-	-	-	-	-

15	14	13	12	11	10	9	8
-	-	-	-	-	-	-	-

7	6	5	4	3	2	1	0
-	-	-	CE	FSPR	CRC	DIS	EN

Writing a zero to a bit in this register has no effect.

- **CE: Chip Erase**
  Writing a one to this bit triggers the FLASH Erase All (EA) operation which clears all volatile memories, the whole flash array, the general purpose fuses and the protected state. The Status register DONE field indicates the completion of the operation.
  Reading this bit always returns 0
- **FSPR: Flash User Page Read**
  Writing a one to this bit triggers a read operation in the User page. The word pointed by the ADDR register in the page is read and written to the DATA register. ADDR is post incremented allowing a burst of reads without modifying ADDR. SR.DONE must be read high prior to reading the DATA register.
  Reading this bit always returns 0
- **CRC: Cyclic Redundancy Code**
  Writing a one triggers a CRC calculation over a memory area defined by the ADDR and LENGTH registers. Reading this bit always returns 0
  Note: This feature is restricted while in protected state
- **DIS: Disable**
  Writing a one to this bit disables the module. Disabling the module resets the whole module immediately.
- **EN: Enable**
  Writing a one to this bit enables the module.

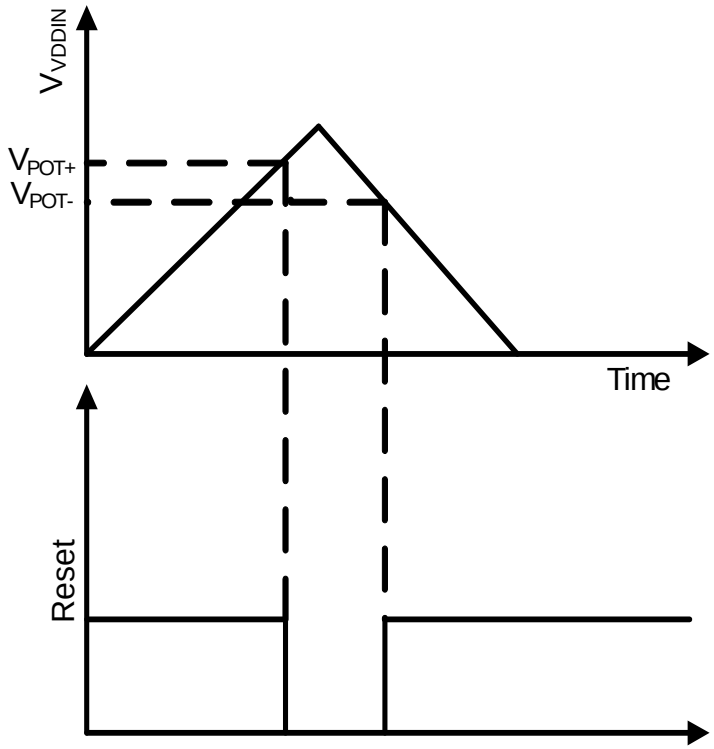
9.9.2 Power-on Reset 33 Characteristics

Table 9-41. POR33 Characteristics (1)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
V_{POT+}	Voltage threshold on V_{VDDIN} rising		1.25		1.55	V
V_{POT-}	Voltage threshold on V_{VDDIN} falling		0.95		1.30	

1. These values are based on characterization. These values are not covered by test limits in production.

Figure 9-4. POR33 Operating Principle



9.9.3 Brown Out Detectors Characteristics

Table 9-42. BOD18 Characteristics (1)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
	Step size, between adjacent values in BSCIF.BOD18LEVEL(1)			10.1		mV
V_{HYST}	BOD hysteresis(1)	T = 25°C	3		40	
t_{DET}	Detection time(1)	Time with $V_{VDDCORE}$ < BOD18.LEVEL necessary to generate a reset signal	1.2			µs
I_{BOD}	Current consumption(1)	on VDDIN		7.4	14	µA
		on VDDCORE			7	
$t_{STARTUP}$	Startup time(1)				4.5	µs

Table 9-46. DC Characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Units
VDDANA	Supply voltage [1]		1.6		3.6	V
	Reference range [2]	Differential mode	1.0		VDDANA -0.6	V
		Unipolar and Window modes	1.0		1.0	
		Using divide by two function (differential)	2.0		VDDANA	
	Absolute min, max input voltage[2]		-0,1		VDDANA +0.1	V
	Start up time[2]	ADC with reference already enabled		12	24	Cycles
		No gain compensation Reference buffer			5	µs
		Gain compensation Reference buffer			60	Cycles
R_{SAMPLE}	Input channel source resistance[2]				0.5	kΩ
C_{SAMPLE}	Sampling capacitance[2]		2.9	3.6	4.3	pF
	Reference input source resistance[2]	Gain compensation			2	kΩ
		No gain compensation			1	MΩ
	ADC reference settling time[2]	After changing reference/mode [3]		5	60	Cycles

1. These values are based on characterization. These values are not covered by test limits in production
2. These values are based on simulation. These values are not covered by test limits in production
3. Requires refresh/flush otherwise conversion time (latency) + 1

Table 9-47. Differential mode, gain=1

Symbol	Parameter	Conditions	Min	Typ	Max	Units
	Accuracy without compensation [1]			7		ENOB
	Accuracy after compensation[1]	(INL, gain and offset)			11	ENOB
INL	Integral Non Linearity [2]	After calibration, Gain compensation		1.2	1.7	LSBs
DNL	Differential Non Linearity[2]	After calibration		0.7	1.0	LSBs
	Gain error [2]	External reference	-5.0	-1.0	5.0	mV
		VDDANA/1.6	-40		40	
		VDDANA/2.0	-40		40	
		Bandgap After calibration	-30		30	
	Gain error drift vs voltage[1]	External reference	-2		2	mV/V
	Gain error drift vs temperature[1]	After calibration + bandgap drift If using onchip bandgap			0.08	mV/°K
	Offset error [2]	External reference	-5.0		5.0	mV
		VDDANA/1.6	-10		10	
		VDDANA/2.0	-10		10	
		Bandgap After calibration	-10		10	
	Offset error drift vs voltage[1]		-4		4	mV/V

Where $SPIn$ is the MISO delay, SPI6 or SPI9 depending on CPOL and NCPHA. t_{SETUP} is the SPI master setup time. refer to the SPI master datasheet for t_{SETUP} . f_{PINMAX} is the maximum frequency of the SPI pins. refer to the I/O Pin Characteristics section for the maximum frequency of the pins.

9.10.4 TWIM/TWIS Timing

Figure 9-64 shows the TWI-bus timing requirements and the compliance of the device with them. Some of these requirements (t_r and t_f) are met by the device without requiring user intervention. Compliance with the other requirements (t_{HD-STA}, t_{SU-STA}, t_{SU-STO}, t_{HD-DAT}, $t_{SU-DAT-TWI}$, $t_{LOW-TWI}$, t_{HIGH}, and f_{TWCK}) requires user intervention through appropriate programming of the relevant TWIM and TWIS user interface registers. refer to the TWIM and TWIS sections for more information.

Table 9-64. TWI-Bus Timing Requirements

Symbol	Parameter	Mode	Minimum		Maximum		Unit
			Requirement	Device	Requirement	Device	
t_r	TWCK and TWD rise time	Standard(1)	-		1000		ns
		Fast(1)	$20 + 0.1C_b$		300		
t_f	TWCK and TWD fall time	Standard	-		300		ns
		Fast	$20 + 0.1C_b$		300		
t_{HD-STA}	(Repeated) START hold time	Standard	4	t_{clkpb}	-		µs
		Fast	0.6				
t_{SU-STA}	(Repeated) START set-up time	Standard	4.7	t_{clkpb}	-		µs
		Fast	0.6				
t_{SU-STO}	STOP set-up time	Standard	4.0	$4t_{clkpb}$	-		µs
		Fast	0.6				
t_{HD-DAT}	Data hold time	Standard	0.3(2)	$2t_{clkpb}$	3.45()	$15t_{prescaled} + t_{clkpb}$	µs
		Fast			0.9()		
$t_{SU-DAT-TWI}$	Data set-up time	Standard	250	$2t_{clkpb}$	-		ns
		Fast	100				
t_{SU-DAT}		-	-	t_{clkpb}	-		-
$t_{LOW-TWI}$	TWCK LOW period	Standard	4.7	$4t_{clkpb}$	-		µs
		Fast	1.3				
t_{LOW}		-	-	t_{clkpb}	-		-
t_{HIGH}	TWCK HIGH period	Standard	4.0	$8t_{clkpb}$	-		µs
		Fast	0.6				
f_{TWCK}	TWCK frequency	Standard	-		100	$\frac{1}{12t_{clkpb}}$	kHz
		Fast			400		

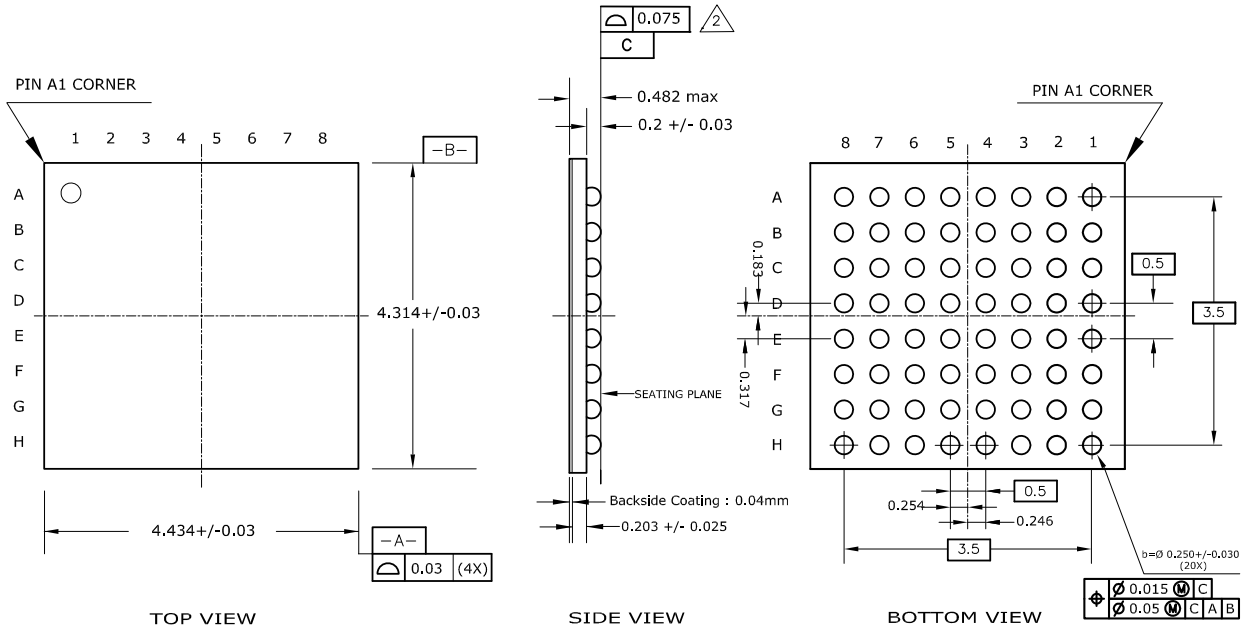
Notes: 1. Standard mode: $f_{TWCK} \leq 100$ kHz ; fast mode: $f_{TWCK} > 100$ kHz .

Table 9-66. SWD Timings[1]

Symbol	Parameter	Conditions	Min	Max	Units
Thigh	SWDCLK High period	V_{VDDIO} from 3.0 V to 3.6 V, maximum external capacitor = 40 pF	10	500 000	ns
Tlow	SWDCLK Low period		10	500 000	
Tos	SWDIO output skew to falling edge SWDCLK		-5	5	
Tis	Input Setup time required between SWDIO		4	-	
Tih	Input Hold time required between SWDIO and rising edge SWDCLK		1	-	

Note: 1. These values are based on simulation. These values are not covered by test limits in production or characterization.

Figure 10-3. WLCSP64 SAM4LC4/2 Package Drawing



COMMON DIMENSIONS
(Unit of Measure = mm)

BALL	SIGNAL	X COORD	Y COORD
A1	PB04	1.746	1.683
A2	GNDANA	1.246	1.683
A3	ADVREFP	0.746	1.683
A4	VDDANA	0.246	1.683
A5	PA09	-0.254	1.683
A6	CAPL	-0.754	1.683
A7	CAPH	-1.254	1.683
A8	PA12	-1.754	1.683
B1	PB03	1.746	1.183
B2	XIN32	1.246	1.183
B3	XOUT32	0.746	1.183
B4	PA08	0.246	1.183
B5	PB06	-0.254	1.183
B6	PA10	-0.754	1.183
B7	PA11	-1.254	1.183
B8	VLCD	-1.754	1.183
C1	VDDIN	1.746	0.683
C2	PB01	1.246	0.683
C3	PA05	0.746	0.683
C4	PA06	0.246	0.683
C5	PA07	-0.254	0.683
C6	PB07	-0.754	0.683

BALL	SIGNAL	X COORD	Y COORD
C7	PA13	-1.254	0.683
C8	BIAS1	-1.754	0.683
D1	VDDOUT	1.746	0.183
D2	PB00	1.246	0.183
D3	PA04	0.746	0.183
D4	PB05	0.246	0.183
D5	PB12	-0.254	0.183
D6	PB08	-0.754	0.183
D7	PA14	-1.254	0.183
D8	BIAS2	-1.754	0.183
E1	GNDIN	1.746	-0.317
E2	PA03	1.246	-0.317
E3	PB02	0.746	-0.317
E4	RESET_N	0.246	-0.317
E5	PB13	-0.254	-0.317
E6	PB09	-0.754	-0.317
E7	PA15	-1.254	-0.317
E8	GNDIO0	-1.754	-0.317
F1	VDDCORE	1.746	-0.817
F2	TCK	1.246	-0.817
F3	PA02	0.746	-0.817
F4	PB14	0.246	-0.817

BALL	SIGNAL	X COORD	Y COORD
F5	PA22	-0.254	-0.817
F6	PB10	-0.754	-0.817
F7	PA16	-1.254	-0.817
F8	VLCDIN	-1.754	-0.817
G1	GNDIO1	1.746	-1.317
G2	PA26	1.246	-1.317
G3	PA24	0.746	-1.317
G4	PA00	0.246	-1.317
G5	PA01	-0.254	-1.317
G6	PA19	-0.754	-1.317
G7	PA18	-1.254	-1.317
G8	PA17	-1.754	-1.317
H1	VDDIO1	1.746	-1.817
H2	PA25	1.246	-1.817
H3	PA23	0.746	-1.817
H4	PB15	0.246	-1.817
H5	PA21	-0.254	-1.817
H6	VDDIO0	-0.754	-1.817
H7	PA20	-1.254	-1.817
H8	PB11	-1.754	-1.817

Notes : 1. Dimension "b" is measured at the maximum ball diameter in a plane to the seating plane.

2. Applied to whole wafer.

Table 10-8. Device and Package Maximum Weight

14.8	mg

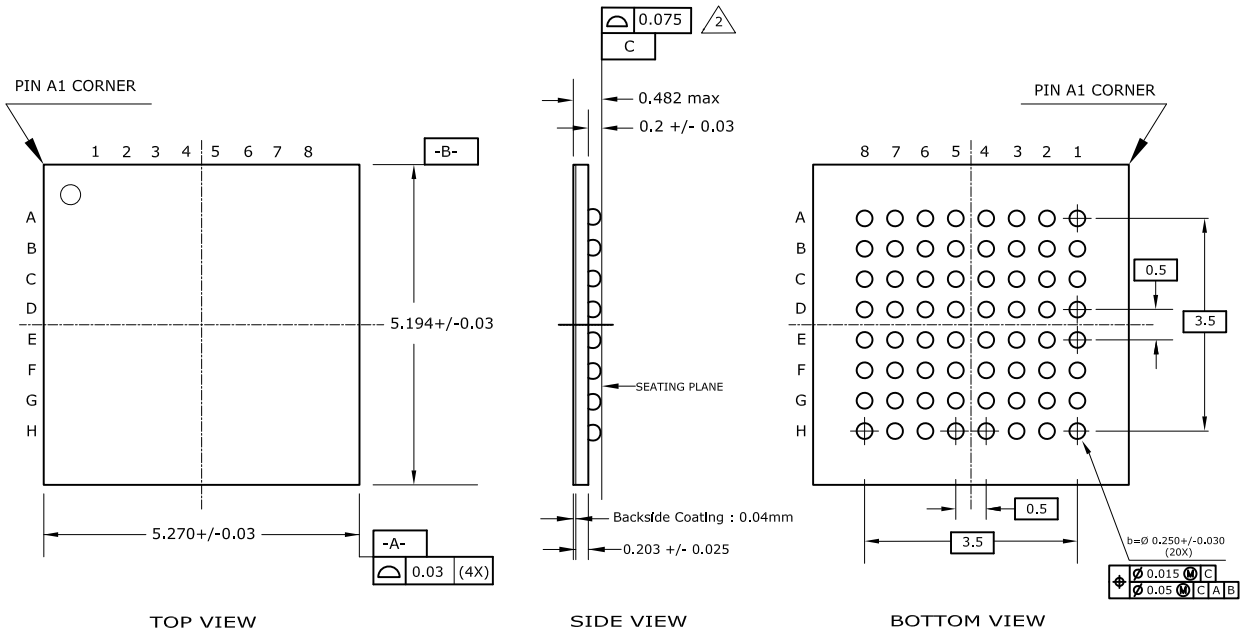
Table 10-9. Package Characteristics

Moisture Sensitivity Level	MSL3

Table 10-10. Package Reference

JEDEC Drawing Reference	MS-026
JESD97 Classification	E1

Figure 10-6. WLCSP64 SAM4LS8 Package Drawing



COMMON DIMENSIONS
(Unit of Measure = mm)

BALL	SIGNAL	X COORD	Y COORD
A1	PB04	1.75	1.75
A2	GNDANA	1.75	1.25
A3	ADVREFP	1.75	0.75
A4	VDDANA	1.75	0.25
A5	PA09	1.75	-0.25
A6	PA28	1.75	-0.75
A7	PA27	1.75	-1.25
A8	PA12	1.75	-1.75
B1	PB03	1.25	1.75
B2	XIN32	1.25	1.25
B3	XOUT32	1.25	0.75
B4	PA08	1.25	0.25
B5	PB06	1.25	-0.25
B6	PA10	1.25	-0.75
B7	PA11	1.25	-1.25
B8	PA29	1.25	-1.75
C1	VDDIN	0.75	1.75
C2	PB01	0.75	1.25
C3	PA05	0.75	0.75
C4	PA06	0.75	0.25
C5	PA07	0.75	-0.25
C6	PB07	0.75	-0.75

BALL	SIGNAL	X COORD	Y COORD
C7	PA13	0.75	-1.25
C8	GNDIO0	0.75	-1.75
D1	VDDOUT	0.25	1.75
D2	PB00	0.25	1.25
D3	PA04	0.25	0.75
D4	PB05	0.25	0.25
D5	PB12	0.25	-0.25
D6	PB08	0.25	-0.75
D7	PA14	0.25	-1.25
D8	VLCDIN	0.25	-1.75
E1	GNDIN	-0.25	1.75
E2	PA03	-0.25	1.25
E3	PB02	-0.25	0.75
E4	RESET_N	-0.25	0.25
E5	PB13	-0.25	-0.25
E6	PB09	-0.25	-0.75
E7	PA15	-0.25	-1.25
E8	PA30	-0.25	-1.75
F1	VDDCORE	-0.75	1.75
F2	TCK	-0.75	1.25
F3	PA02	-0.75	0.75
F4	PB14	-0.75	0.25

BALL	SIGNAL	X COORD	Y COORD
F5	PA22	-0.75	-0.25
F6	PB10	-0.75	-0.75
F7	PA16	-0.75	-1.25
F8	PA31	-0.75	-1.75
G1	GNDIO1	-1.25	1.75
G2	PA26	-1.25	1.25
G3	PA24	-1.25	0.75
G4	PA00	-1.25	0.25
G5	PA01	-1.25	-0.25
G6	PA19	-1.25	-0.75
G7	PA18	-1.25	-1.25
G8	PA17	-1.25	-1.75
H1	VDDIO1	-1.75	1.75
H2	PA25	-1.75	1.25
H3	PA23	-1.75	0.75
H4	PB15	-1.75	0.25
H5	PA21	-1.75	-0.25
H6	VDDIO0	-1.75	-0.75
H7	PA20	-1.75	-1.25
H8	PB11	-1.75	-1.75

Notes : 1. Dimension "b" is measured at the maximum ball diameter in a plane to the seating plane.

2. Applied to whole wafer.

Table 10-17. Device and Package Maximum Weight

14.8	mg

Table 10-18. Package Characteristics

Moisture Sensitivity Level	MSL3

Table 10-19. Package Reference

JEDEC Drawing Reference	MS-026
JESD97 Classification	E1

13. Datasheet Revision History

Note that the referring page numbers in this section are referred to this document. The referring revision in this section are referring to the document revision.

13.1 Rev. A – 09/12

1. Initial revision.

13.2 Rev. B – 10/12

1. Fixed ordering code
2. Changed BOD18CTRL and BOD33CTRL ACTION field from “Reserved” to ‘No action”

13.3 Rev. C – 02/13

1. Fixed ball pitch for VFBGA100 package
2. Added VFBGA100 and WLCSP64 pinouts
3. Added Power Scaling Mode 2 for high frequency support
4. Minor update on several modules chapters
5. Major update on Electrical characteristics
6. Updated errata
7. Fixed GPIO multiplexing pin numbers

13.4 Rev. D – 03/13

1. Removed WLCSP package information
2. Added errata text for detecting whether a part supports PS2 mode or not
3. Removed temperature sensor feature (not supported by production flow)
4. Fixed MUX selection on Positive ADC input channel table
5. Added information about TWI instances capabilities
6. Added some details on errata Corrupted data in flash may happen after flash page write operations.171